

AMENDMENTS TO THE CLAIMS

1.-7. (Canceled)

8. (Currently Amended) A method comprising:
resetting each of a plurality of configuration registers of a test device to a register default data value; then

loading the plurality of configuration registers according to information stored in a non-volatile test memory, wherein the information in a memory includes a plurality of address information and a plurality of data corresponding to the plurality of address information, each of the plurality of address information identifying at least one of the plurality of configuration registers to which a corresponding data should be written, further comprising repeating the resetting and loading at least three times to repeat a multi-stage test data loading process with subsequent test information stored in the non-volatile memory during a memory design ~~validation stage~~validation stage; then manufacturing a plurality of products based on the subsequent test information.

9. (Original) The method of claim 8, wherein loading occurs during initialization of a communication controller device.

10. (Previously Presented) The method of claim 8, further comprising:
updating the information stored in the non-volatile memory with a second plurality of address information and a second a plurality of data corresponding to the second plurality of address information, each of the second plurality of address information identifying at least one of the plurality of registers to which a corresponding one of the second plurality of data should be written.

11. (Currently Amended) A method comprising:
a) selecting a desired configuration of a device, the desired configuration associated with desired data to be stored in a plurality of registers of the device;
b) storing test information associated with the desired configuration in a memory;
c) resetting each of the plurality of registers to a register default data value;

d) loading at least two of the plurality of registers according to the test information during a memory design validation stage, wherein the test information includes a plurality of test address information and a plurality of test data corresponding to the plurality of test address information, each of the plurality of test address information identifying at least one of the plurality of registers to which a corresponding test data should be written;

e) identifying a subset of the plurality of test data that correspond to a subset of the plurality of registers having default data values equal to desired data for achieving the desired configuration prior to loading;

f) repeating b), c), d) and e); then

g) manufacturing a plurality of products based on the test information and the subset.

12. (Original) The method of claim 11, wherein the test information includes a register address and corresponding register data for each one of the plurality of registers.

13. (Original) The method of claim 11, wherein each of the plurality of test data is a data word of register data, and each of the plurality of test address information is a data word of register test address information corresponding one of the data words of register data.

14. (Canceled)

15. (Previously Presented) The method of claim 11, further comprising identifying an additional subset of test data that corresponds to a subset of the plurality of registers having default data values equal to desired data for achieving the desired configuration, after loading.

16. (Original) The method of claim 11, wherein resetting and loading occur during initialization of a communication controller device.

17. (Previously Presented) The method of claim 11, further comprising generating a desired information associated with the desired configuration, wherein generating comprises:

if there exists at least one of the plurality of test data corresponding to one of the plurality of registers having default data values equal to desired data for achieving the desired configuration prior to loading, then, for at least three times, storing subsequent test information and repeating c), d), and e) using the subsequent test information; else identifying the desired information to be the test information.

18. (Original) The method of claim 17, further comprising selecting a desired memory that is less than or equal to a memory size sufficient store the desired information.

19. (Original) The method of claim 18, wherein selecting a desired memory includes reducing a size of the memory by a memory size sufficient to store the subset of the plurality of test data and the corresponding test address information.

20.-21. (Canceled)

22. (Canceled)

23. (Canceled)

24. (Previously Presented) The method of claim 11 further comprising storing subsequent test information and repeating c), d), and e) using the subsequent test information.

25. (Previously Presented) The method of claim 11 further comprising repeating a multi-stage test data loading process, wherein repeating comprises storing subsequent test information and repeating c), d), and e) using the subsequent test information.